RELIABILITY DATA
LTC1966
10/26/2003

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS (1) AT +125°C	NUMBER OF (2) FAILURES
SOIC/SOT/MSOP	231	0201	0318	231.00	0
SSOP/TSSOP	77	0318	0318	77.00	0
	308			308.00	0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	644	0221	0315	221.08	0
SSOP/TSSOP	290	0243	0317	81.52	0
	934			302.60	0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	236	0221	0315	195.19	0
SSOP/TSSOP	182	0243	0243	76.26	0
	418			271.45	0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	250	0226	0311	213.40	0
	250			213.40	0

(1) Assumes Activation Energy = 0.7 Electron Volts
(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 38.43 FITS
(3) Mean Time Between Failures in Years = 2,968
Note: 1 FIT = 1 Failure in One Billion Hours.